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Microwave Relaxometer
MWR-2S-3
Lifetime mapping tester for silicon ingots

Microwave Relaxometer MWR-2S-3 is the device for non-equilibrium charge carrier lifetime contactless determination in square silicon ingots and wafers by measuring photoconductivity decay constant after pulse photoexcitation of non-equilibrium charge carriers.

The MWR-2S-3 can be used for inspection of single- and polycrystalline silicon ingots and wafers for solar cell manufacture, quality of wafer processing in solar cell production line.

TECHNICAL DATA

Parameter	Nominal	Accuracy
Laser Light Dio de Radiation:		
Wavelength	975 nm	
Power in measurement area adjustment range	(50 ÷ 500) mW	± 30
Pulse width adjustment range	(2 ÷ 64) μs	
Microwave Generator Operation Frequency,	10 GHz	0.5
Specimen dimensions rang		
-width	< 210 mm	
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-length	(160 ÷ 300) mm	
Minimal measurement step	1 mm	
Measurable Specimen Resistivity Range	(0,5 ÷ 12) Ω.cm:	
Mains	~230 V (50÷60) Hz	± 10V
Power Consumption (excluding PC and monitor consumed power)	≤ 100 W	
Dimensions, mm	365 x 645 x 565	
Weight	30 kg